



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of :

Colin Yates
Nicholas Pasch
Nicholas Eib

Serial No. :

10/006,398

Filed :

November 30, 2001

For :

Alignment Process For Integrated
Circuit Structures On
Semiconductor Substrate Using
Scatterometry Measurements of
Latent Images in Spaced Apart Test
Fields on Substrate

Group Art Unit :

2877

Examiner :

Lauchman, Layla G.

Atty Docket :

/ 01-234

I hereby certify that this correspondence is being deposited with the U.S. Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450, on the date below:

Manu Kashyap

9/20/04
Date

Signature

SUBMISSION OF FORMAL DRAWINGS PURSUANT TO 37 C.F.R. §1.85

Official Draftsman

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Sir:

Applicant hereby substitutes the enclosed formal drawings for those presently in the above referenced application.

LSI Logic Corporation
1621 Barber Lane, MS D-106
Milipitas, CA 95035
408-433-7475

Date: 20 Sept 04

Respectfully submitted,

Timothy Croll

Reg. No. 36,771